

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10547441	NOWINSKI ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
ATIBA O FITZPATRICK	2624	

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	100,128-134	4/3/2010	ATIBA O FITZPATRICK
128	922	4/3/2010	ATIBA O FITZPATRICK
356	39-50	4/3/2010	ATIBA O FITZPATRICK
250	455-465	4/3/2010	ATIBA O FITZPATRICK
600	407-435	4/3/2010	ATIBA O FITZPATRICK

<b>SEARCH NOTES</b>			
<b>Search Notes</b>		<b>Date</b>	<b>Examiner</b>
East		4/3/2010	ATIBA O FITZPATRICK
East		4/3/2010	ATIBA O FITZPATRICK
East		4/3/2010	ATIBA O FITZPATRICK
East		4/3/2010	ATIBA O FITZPATRICK
East		4/3/2010	ATIBA O FITZPATRICK
INSPEC		4/3/2010	ATIBA O FITZPATRICK
IEEE XPLORER		4/3/2010	ATIBA O FITZPATRICK

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	PGPub text search, see interference search printout	4/3/2010	ATIBA O FITZPATRICK

/A. O. F./  
Examiner Art Unit 2624